Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/699,868	CHEN ET AL.	
Examiner	Art Unit	
John C. Hanley	2856	

	SEAR	CHED	
Class	Subclass	Date	Examiner
73	504.12	9/21/2005	JCH
73	504.16	9/21/2005	JCH
73	504.14	9/21/2005	JCH
73	504.02	9/21/2005	JCH
73	504.04	9/21/2005	JCH
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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